## Application/Control No. 10/002,024 Examiner Applicant(s)/Patent Under Reexamination FUTAGAWA ET AL. Art Unit

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## Notice of References Cited

115	PATENT	DOCL	IMENTS

Christopher P Bruenjes

		,		U.S. PATERT DOCUMENTO	<del></del>
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,120,860	09-2000	Bowen et al.	428/34.2
	В	US-5,387,449	02-1995	Kunz et al.	428/35.4
	С	US-5,391,423	02-1995	Wnuk et al.	428/217
	D	US-6,146,726	11-2000	Yoshii et al.	428/35.9
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.